

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHOU, DAVID	
		Examiner Thu V Huynh	Art Unit 2178	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,715,129	03-2004	Hind et al.	715/513
B	US-2003/0101203	05-2003	Chen et al.	707/513
C	US-2002/0095458	07-2002	Silverstein et al.	709/203
D	US-6,061,738	05-2000	Osaku et al.	709/245
E	US-2002/0087683	07-2002	Szondy, Gyorgy	709/225
F	US-2003/0011631	01-2003	Halahmi, Erez	345/744
G	US-2003/0182449	09-2003	Anderson et al.	709/245
H	US-2002/0001295	01-2002	Park, Woo-kyeong	370/338
I	US-6,453,361	09-2002	Morris, Robert Paul	709/250
J	US-6,430,624	08-2002	Jamtgaard et al.	709/246
K	US-2004/0024848	02-2004	Smith et al.	709/219
L	US-2002/0059344	05-2002	BRITTON et al.	707/513
M	US-2001/0015972	08-2001	Horiguchi et al.	370/352

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	60,251,566		
V			
W			
X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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